

Search Notes

Application/Control No.

10/790,030

Examiner

EDMUND H. LEE

Applicant(s)/Patent under
Reexamination

AOKI ET AL

Art Unit

1732

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR